

2N7002F

N-channel TrenchMOS FET Rev. 03 — 28 April 2006

Product data sheet

Product profile

1.1 General description

N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology.

1.2 Features

- Logic level threshold compatible
- Surface-mounted package
- Very fast switching
- TrenchMOS technology

1.3 Applications

Logic level translator

High-speed line driver

1.4 Quick reference data

- $V_{DS} \le 60 \text{ V}$
- \blacksquare R_{DSon} \leq 2 Ω

- $I_D \le 475 \text{ mA}$
- $P_{tot} \le 0.83 \text{ W}$

Pinning information

Table 1: **Pinning**

	3		
Pin	Description	Simplified outline	Symbol
1	gate (G)	_	_
2	source (S)		D D
3	drain (D)	1 📗	G
		SOT23	mbb076 S



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Table 2: Ordering information

Type number	Package		
	Name	Description	Version
2N7002F	TO-236AB	plastic surface-mounted package; 3 leads	SOT23

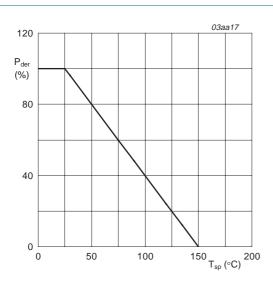
4. Limiting values

Table 3: Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

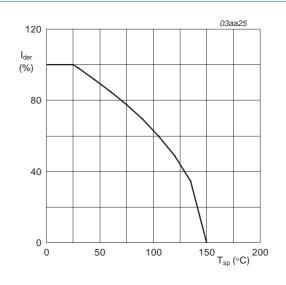
Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	25 °C ≤ T _j ≤ 150 °C	-	60	V
V_{DGR}	drain-gate voltage (DC)	25 °C \leq T _j \leq 150 °C; R _{GS} = 20 kΩ	-	60	V
V_{GS}	gate-source voltage		-	±30	V
V_{GSM}	peak gate-source voltage	$t_p \le 50 \ \mu s$; pulsed; duty cycle = 25 %	-	±40	V
I _D	drain current	T_{sp} = 25 °C; V_{GS} = 10 V; see <u>Figure 2</u> and <u>3</u>	-	475	mΑ
		$T_{sp} = 100 ^{\circ}\text{C}; V_{GS} = 10 ^{\circ}\text{V}; \text{see} \frac{\text{Figure 2}}{}$	-	300	mΑ
I _{DM}	peak drain current	T_{sp} = 25 °C; pulsed; $t_p \le 10 \mu s$; see Figure 3	-	1.9	Α
P _{tot}	total power dissipation	T _{sp} = 25 °C; see <u>Figure 1</u>	-	0.83	W
T _{stg}	storage temperature		-65	+150	°C
Tj	junction temperature		-65	+150	°C
Source-o	drain diode				
Is	source current	T _{sp} = 25 °C	-	475	mΑ
I _{SM}	peak source current	T_{sp} = 25 °C; pulsed; $t_p \le 10 \ \mu s$	-	1.9	Α





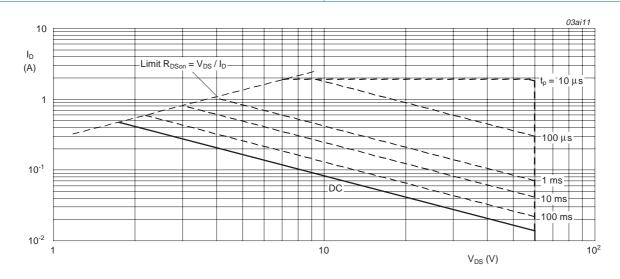
$$P_{der} = \frac{P_{tot}}{P_{tot(25\ ^{\circ}C)}} \times 100\ \%$$

Fig 1. Normalized total power dissipation as a function of solder point temperature



$$I_{der} = \frac{I_D}{I_{D(25\ ^{\circ}C)}} \times 100\ \%$$

Fig 2. Normalized continuous drain current as a function of solder point temperature



 T_{sp} = 25 °C; I_{DM} is single pulse

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

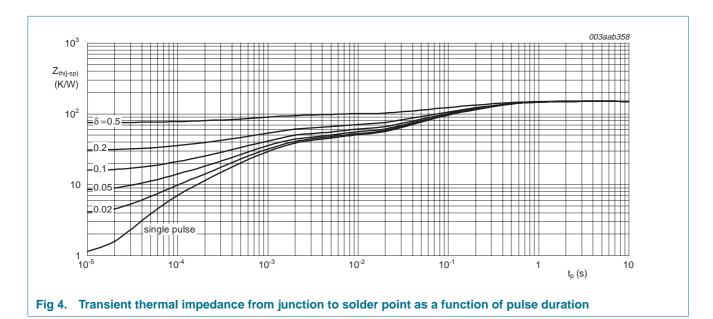


5. Thermal characteristics

Table 4: Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-sp)}$	thermal resistance from junction to solder point	see Figure 4	-	-	150	K/W
R _{th(j-a)}	thermal resistance from junction to ambient		<u>[1]</u> _	-	350	K/W

[1] Mounted on a printed-circuit board; minimum footprint; vertical in still air



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Table 5: Characteristics

 $T_j = 25 \,^{\circ}C$ unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cl	naracteristics					
V _{(BR)DSS}	drain-source breakdown	$I_D = 10 \mu\text{A}; V_{GS} = 0 V$				
	voltage	T _j = 25 °C	60	-	-	V
		T _j = −55 °C	55	-	-	V
V _{GS(th)}	gate-source threshold voltage	$I_D = 0.25$ mA; $V_{DS} = V_{GS}$; see Figure 9 and 10				
		T _j = 25 °C	1	2	2.5	V
		T _j = 150 °C	0.6	-	-	V
		T _j = −55 °C	-	-	2.75	V
I _{DSS}	drain leakage current	$V_{DS} = 48 \text{ V}; V_{GS} = 0 \text{ V}$				
		T _j = 25 °C	-	0.01	1	μΑ
		T _j = 150 °C	-	-	10	μΑ
I _{GSS}	gate leakage current	$V_{GS} = \pm 15 \text{ V}; V_{DS} = 0 \text{ V}$	-	10	100	nΑ
R _{DSon}	drain-source on-state resistance	V_{GS} = 10 V; I_D = 500 mA; see Figure 6 and 8				
		T _j = 25 °C	-	0.78	2	Ω
		T _j = 150 °C	-	1.45	3.7	Ω
		$V_{GS} = 4.5 \text{ V}; I_D = 75 \text{ mA}; \text{ see } \frac{\text{Figure 6}}{\text{A}} \text{ and } \frac{8}{\text{A}}$	-	1.2	4	Ω
Dynami	c characteristics					
Q _{G(tot)}	total gate charge	$I_D = 300 \text{ mA}; V_{DS} = 30 \text{ V}; V_{GS} = 10 \text{ V};$		0.69	-	nC
Q _{GS}	gate-source charge	see <u>Figure 11</u> and <u>12</u>	-	0.1	-	nC
Q _{GD}	gate-drain charge		-	0.27	-	nC
C _{iss}	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 10 \text{ V}; f = 1 \text{ MHz};$	-	31	50	pF
C _{oss}	output capacitance	see Figure 14	-	6.8	30	pF
C _{rss}	reverse transfer capacitance		-	3.5	10	pF
t _{on}	turn-on time	V_{DS} = 50 V; R_{L} = 250 Ω ; V_{GS} = 10 V;	-	2.5	10	ns
t _{off}	turn-off time	$R_G = 50 \Omega$; $R_{GS} = 50 \Omega$	-	11	15	ns
Source-	drain diode					
V_{SD}	source-drain voltage	$I_S = 300 \text{ mA}$; $V_{GS} = 0 \text{ V}$; see Figure 13	-	0.85	1.5	V
	reverse recovery time	$I_S = 300 \text{ mA}$; $dI_S/dt = -100 \text{ A/}\mu\text{s}$; $V_{GS} = 0 \text{ V}$	-	30	-	ns
t _{rr}	TOTOLOG TOGOTOLY MILLO	, , , ,				

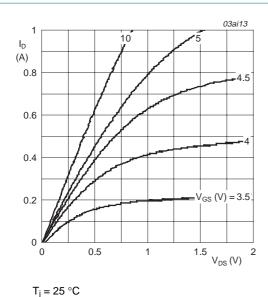
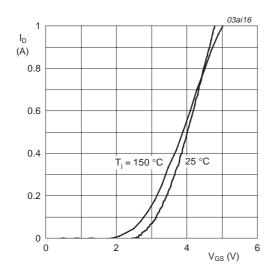
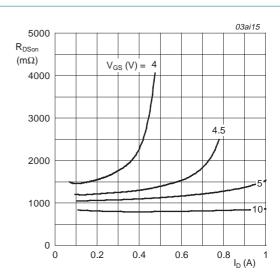


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values



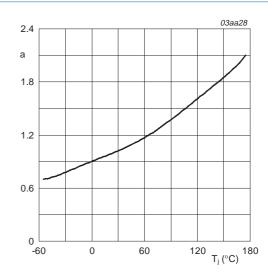
 T_j = 25 °C and 150 °C; $V_{DS} > I_D \times R_{DSon}$

Fig 7. Transfer characteristics: drain current as a function of gate-source voltage; typical values



T_j = 25 °C

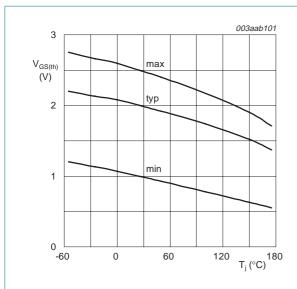
Fig 6. Drain-source on-state resistance as a function of drain current; typical values



 $a = \frac{R_{DSon}}{R_{DSon(25\,^{\circ}C)}}$

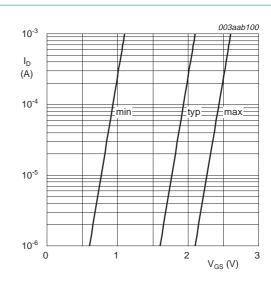
Fig 8. Normalized drain-source on-state resistance factor as a function of junction temperature

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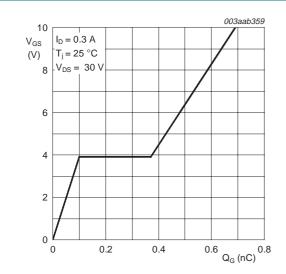
 $I_D = 0.25 \text{ mA}; V_{DS} = V_{GS}$

Fig 9. Gate-source threshold voltage as a function of junction temperature



 $T_j = 25$ °C; $V_{DS} = 5$ V

Fig 10. Sub-threshold drain current as a function of gate-source voltage



 $I_D = 300 \text{ mA}; V_{DS} = 30 \text{ V}$

Fig 11. Gate-source voltage as a function of gate charge; typical values

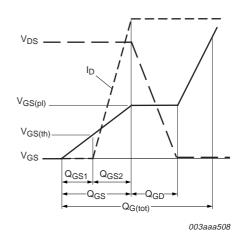
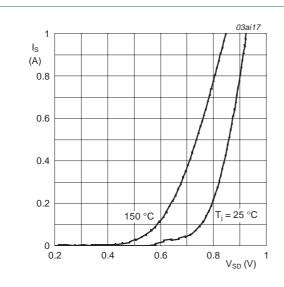


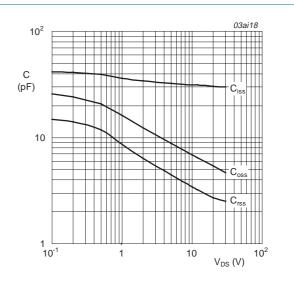
Fig 12. Gate charge waveform definitions

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 $T_j = 25~^{\circ}C~\text{and}~150~^{\circ}C;~V_{GS} = 0~V$ Fig 13. Source current as a function of source-drain

voltage; typical values



 $V_{GS} = 0 \text{ V}; f = 1 \text{ MHz}$

Fig 14. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

7. Package outline

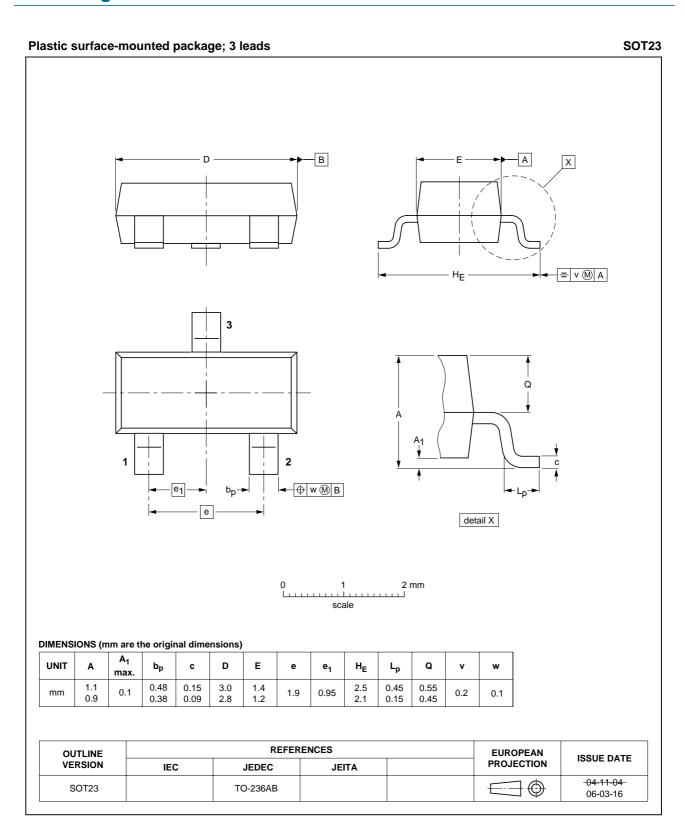


Fig 15. Package outline SOT23



8. Revision history

Table 6: Revision history

Document ID	Release date	Data sheet status	Change notice	Doc. number	Supersedes
2N7002F_3	20060428	Product data sheet	-	-	2N7002F_2
Modifications:	• Table 5 "C	Characteristics": V _{GS(th)} I	D condition modified		
	 Table 5 "C 	characteristics": V _{GS(th)} r	naximum limits modi	fied	
	 Table 5 "C 	Characteristics": R _{DSon} ty	pical values modified	d	
	• Table 5 "C	characteristics": gfs remo	oved		
	• Table 5 "C	haracteristics": Addition	of Q _{G(tot)} , Q _{GS} and 0	\mathfrak{Q}_{GD}	
	 Table 5 "C 	Characteristics": Ciss, Cos	ss and C _{rss} values mo	odified	
	• Table 5 "C	characteristics": ton and t	off typical values mod	dified	
	• Figure 3,	4, <u>5</u> , <u>6</u> , <u>7</u> , <u>9</u> , <u>10</u> , <u>13</u> and	14: modified		
	• Figure 11:	: added			
2N7002F_2	20050509	Product data sheet	-	9397 750 14945	2N7002F-01
2N7002F-01	20020211	Product data	-	9397 750 09096	-

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Level	Data sheet status [1]	Product status [2] [3]	Definition
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